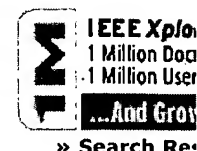




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2 Dynamic neural control for a plasma etch process

Card, J.P.; Sniderman, D.L.; Klimasauskas, C.;

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Pages:237 - 240

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2 Algorithmic fusion of gene expression profiling for diffuse large B-cell lymphoma outcome prediction*Qiuming Zhu; Hongmei Cui; Kajia Cao; Chan, W.C.;*

Information Technology in Biomedicine, IEEE Transactions on , Volume: 8 , Issue: 2 , June 2004

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3 Linearization of receivers using envelope signal injection*Chan, W.H.Y.; Bock, G.;*

Microwave and Wireless Components Letters, IEEE [see also IEEE Microwave and Guided Wave Letters] , Volume: 14 , Issue: 7 , July 2004

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4 Linearization of mixers using predistortion and envelope signal injection*Chan, W.H.Y.; Bock, G.;*

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[\[Abstract\]](#) [\[PDF Full-Text \(176KB\)\]](#) IEEE JNL

5 Interconnected linear multivariable systems with delays: System properties and input-output stability*Desoer, C.; Chan, W.;*

Automatic Control, IEEE Transactions on , Volume: 22 , Issue: 4 , Aug 1977

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[\[Abstract\]](#) [\[PDF Full-Text \(752KB\)\]](#) IEEE JNL

6 Robustness of stability conditions for linear time-invariant feedback systems

Desoer, C.; Callier, F.; Chan, W.;

Automatic Control, IEEE Transactions on , Volume: 22 , Issue: 4 , Aug 1977
Pages:586 - 590

[\[Abstract\]](#) [\[PDF Full-Text \(584KB\)\]](#) IEEE JNL

7 A basis for the controllable canonical form of linear time-invariant multiinput systems

Chan, W.; Wang, Y.;

Automatic Control, IEEE Transactions on , Volume: 23 , Issue: 4 , Aug 1978
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[\[Abstract\]](#) [\[PDF Full-Text \(304KB\)\]](#) IEEE JNL

8 Eigenvalue assignment and stabilization of interconnected systems using local feedbacks

Chan, W.; Desoer, C.;

Automatic Control, IEEE Transactions on , Volume: 24 , Issue: 2 , Apr 1979
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[\[Abstract\]](#) [\[PDF Full-Text \(488KB\)\]](#) IEEE JNL

9 Measurement of Nonplanar Dielectric Samples Using an Open Resonator

Chan, W.F.P.; Chambers, B.;

Microwave Theory and Techniques, IEEE Transactions on , Volume: 35 , Issue: 12 , Dec 1987
Pages:1429 - 1434

[\[Abstract\]](#) [\[PDF Full-Text \(752KB\)\]](#) IEEE JNL

10 A SFH spread spectrum synchronization algorithm for data broadcasting

Siu, Y.M.; Chan, W.S.; Leung, S.W.;

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[\[Abstract\]](#) [\[PDF Full-Text \(96KB\)\]](#) IEEE JNL

11 Optimizing symbolic model checking for statecharts

Chan, W.; Anderson, R.J.; Beame, P.; Jones, D.H.; Notkin, D.; Warner, W.E.;

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[\[Abstract\]](#) [\[PDF Full-Text \(508KB\)\]](#) IEEE JNL

12 Rapid and accurate inter-robot position determination in robot teams

Jason Wu; Chan, W.K.; Thomas, G.;

Instrumentation and Measurement, IEEE Transactions on , Volume: 50 , Issue: 1 , Feb. 2001
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[\[Abstract\]](#) [\[PDF Full-Text \(100KB\)\]](#) IEEE JNL

13 A novel compact PMSM with magnetic bearing for artificial heart application

Shen, J.X.; Tseng, K.J.; Vilathgamuwa, D.M.; Chan, W.K.;
Industry Applications, IEEE Transactions on , Volume: 36 , Issue: 4 , July-Aug.
2000
Pages:1061 - 1068

[\[Abstract\]](#) [\[PDF Full-Text \(612KB\)\]](#) IEEE JNL

14 Internet based transmission substation monitoring

Chan, W.L.; So, A.T.P.; Lai, L.L.;
Power Systems, IEEE Transactions on , Volume: 14 , Issue: 1 , Feb. 1999
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[\[Abstract\]](#) [\[PDF Full-Text \(1188KB\)\]](#) IEEE JNL

15 Real-time frequency and harmonic evaluation using artificial neural networks

Lai, L.L.; Chan, W.L.; Tse, C.T.; So, A.T.P.;
Power Delivery, IEEE Transactions on , Volume: 14 , Issue: 1 , Jan. 1999
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Evolutionary Computation, 2000. Proceedings of the 2000 Congress on , Volume: 2 , 16-19 July 2000

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3 Utilization of the saturation effect on a DC motor drive with a fuzzy controller

Lee, C.K.; Chan, W.T.;

Industrial Automation and Control: Emerging Technologies, 1995., International IEEE/IAS Conference on , 22-27 May 1995

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Schneidewind, N.F.;
 Software Reliability Engineering, 1993. Proceedings., Fourth International Symposium on , 3-6 Nov. 1993

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Boon Wong; Helling, D.; Clark, R.;

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Oberg, D.I.; Majewski, P.P.;

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